

# Scott D Findlay

## List of Publications by Year in descending order

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164  
papers

7,304  
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61984

43  
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56724

83  
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168  
all docs

168  
docs citations

168  
times ranked

5140  
citing authors

#	ARTICLE	IF	CITATIONS
1	Dynamics of annular bright field imaging in scanning transmission electron microscopy. Ultramicroscopy, 2010, 110, 903-923.	1.9	373
2	Quantitative Atomic Resolution Scanning Transmission Electron Microscopy. Physical Review Letters, 2008, 100, 206101.	7.8	342
3	Robust atomic resolution imaging of light elements using scanning transmission electron microscopy. Applied Physics Letters, 2009, 95, .	3.3	334
4	Differential phase-contrast microscopy at atomic resolution. Nature Physics, 2012, 8, 611-615.	16.7	333
5	Spectroscopic Imaging of Single Atoms Within a Bulk Solid. Physical Review Letters, 2004, 92, 095502.	7.8	299
6	Two-Dimensional Mapping of Chemical Information at Atomic Resolution. Physical Review Letters, 2007, 99, 086102.	7.8	239
7	Standardless Atom Counting in Scanning Transmission Electron Microscopy. Nano Letters, 2010, 10, 4405-4408.	9.1	212
8	Three-dimensional imaging of individual hafnium atoms inside a semiconductor device. Applied Physics Letters, 2005, 87, 034104.	3.3	206
9	Lattice-resolution contrast from a focused coherent electron probe. Part I. Ultramicroscopy, 2003, 96, 47-63.	1.9	193
10	Position averaged convergent beam electron diffraction: Theory and applications. Ultramicroscopy, 2010, 110, 118-125.	1.9	184
11	Atomic Structure of a CeO <sub>2</sub> Grain Boundary: The Role of Oxygen Vacancies. Nano Letters, 2010, 10, 4668-4672.	9.1	173
12	Modelling the inelastic scattering of fast electrons. Ultramicroscopy, 2015, 151, 11-22.	1.9	171
13	Electric field imaging of single atoms. Nature Communications, 2017, 8, 15631.	12.8	144
14	Oxygen Vacancy Ordering at Surfaces of Lithium Manganese(III,IV) Oxide Spinel Nanoparticles. Angewandte Chemie - International Edition, 2011, 50, 3053-3057.	13.8	127
15	Three-dimensional ADF imaging of individual atoms by through-focal series scanning transmission electron microscopy. Ultramicroscopy, 2006, 106, 1062-1068.	1.9	122
16	Direct Imaging of Reconstructed Atoms on TiO <sub>2</sub> (110) Surfaces. Science, 2008, 322, 570-573.	12.6	120
17	Imaging of built-in electric field at a p-n junction by scanning transmission electron microscopy. Scientific Reports, 2015, 5, 10040.	3.3	119
18	New area detector for atomic-resolution scanning transmission electron microscopy. Journal of Electron Microscopy, 2010, 59, 473-479.	0.9	118

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19	Towards quantitative, atomic-resolution reconstruction of the electrostatic potential via differential phase contrast using electrons. Ultramicroscopy, 2015, 159, 124-137.	1.9	118
20	Quantum mechanical model for phonon excitation in electron diffraction and imaging using a Born-Oppenheimer approximation. Physical Review B, 2010, 82, .	3.2	113
21	Atomic-scale imaging of individual dopant atoms in a buried interface. Nature Materials, 2009, 8, 654-658.	27.5	109
22	Direct Imaging of Hydrogen within a Crystalline Environment. Applied Physics Express, 2010, 3, 116603.	2.4	108
23	Atomic-Resolution Electron Energy Loss Spectroscopy Imaging in Aberration Corrected Scanning Transmission Electron Microscopy. Physical Review Letters, 2003, 91, 105503.	7.8	101
24	Atomic structure, electronic structure, and defect energetics in $\text{TiO}_2$ boundaries of $\text{TiO}_2$ . Physical Review B, 2008, 78, .	3.2	98
25	High-angle scattering of fast electrons from crystals containing heavy elements: Simulation and experiment. Physical Review B, 2009, 79, .	3.2	96
26	Direct Observation of Dopant Atom Diffusion in a Bulk Semiconductor Crystal Enhanced by a Large Size Mismatch. Physical Review Letters, 2014, 113, 155501.	7.8	91
27	Three-Dimensional Location of a Single Dopant with Atomic Precision by Aberration-Corrected Scanning Transmission Electron Microscopy. Nano Letters, 2014, 14, 1903-1908.	9.1	89
28	Lattice-resolution contrast from a focused coherent electron probe. Part II. Ultramicroscopy, 2003, 96, 65-81.	1.9	81
29	Quantitative Annular Dark Field Electron Microscopy Using Single Electron Signals. Microscopy and Microanalysis, 2014, 20, 99-110.	0.4	80
30	Room-Temperature Polar Ferromagnet $\text{ScFeO}_3$ Transformed from a High-Pressure Orthorhombic Perovskite Phase. Journal of the American Chemical Society, 2014, 136, 15291-15299.	13.7	78
31	Interface Structures of Gold Nanoparticles on $\text{TiO}_2(110)$ . Physical Review Letters, 2009, 102, 136105.	7.8	76
32	Direct electric field imaging of graphene defects. Nature Communications, 2018, 9, 3878.	12.8	74
33	Direct Visualization of Local Electromagnetic Field Structures by Scanning Transmission Electron Microscopy. Accounts of Chemical Research, 2017, 50, 1502-1512.	15.6	72
34	Interpreting atomic-resolution spectroscopic images. Physical Review B, 2007, 76, .	3.2	64
35	Real-time direct observation of Li in $\text{LiCoO}_2$ cathode material. Applied Physics Letters, 2011, 98, .	3.3	61
36	Three-dimensional imaging in double aberration-corrected scanning confocal electron microscopy, Part I: Ultramicroscopy, 2008, 108, 1558-1566.	1.9	60

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37	Channelling effects in atomic resolution STEM. Ultramicroscopy, 2003, 96, 299-312.	1.9	58
38	Detector non-uniformity in scanning transmission electron microscopy. Ultramicroscopy, 2013, 124, 52-60.	1.9	57
39	Quantitative comparisons of contrast in experimental and simulated bright-field scanning transmission electron microscopy images. Physical Review B, 2009, 80, .	3.2	55
40	Atomic resolution electron microscopy in a magnetic field free environment. Nature Communications, 2019, 10, 2308.	12.8	50
41	Quantitative atomic resolution elemental mapping via absolute-scale energy dispersive X-ray spectroscopy. Ultramicroscopy, 2016, 168, 7-16.	1.9	49
42	Spatial incoherence in phase retrieval based on focus variation. Ultramicroscopy, 2006, 106, 914-924.	1.9	48
43	Three-dimensional imaging in double aberration-corrected scanning confocal electron microscopy, Part II: Inelastic scattering. Ultramicroscopy, 2008, 108, 1567-1578.	1.9	47
44	Multiple elastic scattering of core-loss electrons in atomic resolution imaging. Physical Review B, 2008, 77, .	3.2	44
45	Depth sectioning in scanning transmission electron microscopy based on core-loss spectroscopy. Ultramicroscopy, 2007, 108, 17-28.	1.9	43
46	Atomic Structure of Luminescent Centers in High-Efficiency Ce-doped w-AlN Single Crystal. Scientific Reports, 2014, 4, 3778.	3.3	43
47	Probing the Internal Atomic Charge Density Distributions in Real Space. ACS Nano, 2018, 12, 8875-8881.	14.6	43
48	Influence of orientation on the contrast of high-angle annular dark-field images of silicon. Physical Review B, 2007, 76, .	3.2	42
49	Direct oxygen imaging within a ceramic interface, with some observations upon the dark contrast at the grain boundary. Ultramicroscopy, 2011, 111, 285-289.	1.9	42
50	Contrast Reversal in Atomic-Resolution Chemical Mapping. Physical Review Letters, 2008, 101, 236102.	7.8	41
51	Real-space visualization of intrinsic magnetic fields of an antiferromagnet. Nature, 2022, 602, 234-239.	27.8	41
52	Functional Complex Point-Defect Structure in a Huge-Size-Mismatch System. Physical Review Letters, 2013, 110, 065504.	7.8	40
53	Enhanced light element imaging in atomic resolution scanning transmission electron microscopy. Ultramicroscopy, 2014, 136, 31-41.	1.9	40
54	Single atom visibility in STEM optical depth sectioning. Applied Physics Letters, 2016, 109, .	3.3	40

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55	Prospects for lithium imaging using annular bright field scanning transmission electron microscopy: A theoretical study. <i>Ultramicroscopy</i> , 2011, 111, 1144-1154.	1.9	38
56	Energy dispersive X-ray analysis on an absolute scale in scanning transmission electron microscopy. <i>Ultramicroscopy</i> , 2015, 157, 21-26.	1.9	37
57	Quantitative electric field mapping in thin specimens using a segmented detector: Revisiting the transfer function for differential phase contrast. <i>Ultramicroscopy</i> , 2017, 182, 258-263.	1.9	36
58	Modelling imaging based on core-loss spectroscopy in scanning transmission electron microscopy. <i>Ultramicroscopy</i> , 2005, 104, 126-140.	1.9	35
59	Volcano structure in atomic resolution core-loss images. <i>Ultramicroscopy</i> , 2008, 108, 677-687.	1.9	35
60	Accurate Nanoscale Crystallography in Real-Space Using Scanning Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2015, 21, 946-952.	0.4	35
61	Direct Imaging of Dopant Clustering in Metal-Oxide Nanoparticles. <i>ACS Nano</i> , 2012, 6, 7077-7083.	14.6	32
62	Thermal diffuse scattering in transmission electron microscopy. <i>Ultramicroscopy</i> , 2011, 111, 1670-1680.	1.9	30
63	Structure Retrieval at Atomic Resolution in the Presence of Multiple Scattering of the Electron Probe. <i>Physical Review Letters</i> , 2018, 121, 266102.	7.8	29
64	Modelling high-resolution electron microscopy based on core-loss spectroscopy. <i>Ultramicroscopy</i> , 2006, 106, 1001-1011.	1.9	28
65	Modeling Atomic-Resolution Scanning Transmission Electron Microscopy Images. <i>Microscopy and Microanalysis</i> , 2008, 14, 48-59.	0.4	28
66	Atomic-Scale Identification of Individual Lanthanide Dopants in Optical Glass Fiber. <i>ACS Nano</i> , 2013, 7, 5058-5063.	14.6	27
67	Practical aspects of diffractive imaging using an atomic-scale coherent electron probe. <i>Ultramicroscopy</i> , 2016, 169, 107-121.	1.9	27
68	Structure retrieval with fast electrons using segmented detectors. <i>Physical Review B</i> , 2016, 93, .	3.2	24
69	The atomic structure of polar and non-polar InGaN quantum wells and the green gap problem. <i>Ultramicroscopy</i> , 2017, 176, 93-98.	1.9	24
70	Atomic structure of a $\sqrt{3} \times \sqrt{3}$ [110]/(111) grain boundary in CeO <sub>2</sub> . <i>Applied Physics Letters</i> , 2012, 100, .	3.3	22
71	The microstructure of non-polar a-plane (112̂0) InGaN quantum wells. <i>Journal of Applied Physics</i> , 2016, 119, .	2.5	22
72	Probing the effect of electron channelling on atomic resolution energy dispersive X-ray quantification. <i>Ultramicroscopy</i> , 2017, 182, 264-275.	1.9	22

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73	Removing the effects of elastic and thermal scattering from electron energy-loss spectroscopic data. Applied Physics Letters, 2012, 101, .	3.3	21
74	Detecting the direction of oxygen bonding in SrTiO <sub>3</sub> . Physical Review B, 2013, 88, .	3.2	21
75	Direct visualization of lithium via annular bright field scanning transmission electron microscopy: a review. Microscopy (Oxford, England), 2016, 66, 3-14.	1.5	20
76	Measuring nanometre-scale electric fields in scanning transmission electron microscopy using segmented detectors. Ultramicroscopy, 2017, 182, 169-178.	1.9	20
77	Probing the limits of the rigid-intensity-shift model in differential-phase-contrast scanning transmission electron microscopy. Physical Review A, 2018, 97, .	2.5	20
78	The spatial coherence function in scanning transmission electron microscopy and spectroscopy. Ultramicroscopy, 2014, 146, 6-16.	1.9	19
79	Channeling effects in high-angular-resolution electron spectroscopy. Physical Review B, 2006, 73, .	3.2	18
80	Simultaneous visualization of oxygen vacancies and the accompanying cation shifts in a perovskite oxide by combining annular imaging techniques. Applied Physics Letters, 2012, 100, .	3.3	18
81	Atomic resolution imaging using electron energy-loss phonon spectroscopy. Physical Review B, 2015, 91, .	3.2	18
82	Model of phonon excitation by fast electrons in a crystal with correlated atomic motion. Physical Review B, 2009, 80, .	3.2	16
83	Suppressing dynamical diffraction artefacts in differential phase contrast scanning transmission electron microscopy of long-range electromagnetic fields via precession. Ultramicroscopy, 2020, 219, 113097.	1.9	16
84	Angular dependence of fast-electron scattering from materials. Physical Review B, 2020, 101, .	3.2	16
85	Composition measurement in substitutionally disordered materials by atomic resolution energy dispersive X-ray spectroscopy in scanning transmission electron microscopy. Ultramicroscopy, 2017, 176, 52-62.	1.9	15
86	Imaging using inelastically scattered electrons in CTEM and STEM geometry. Ultramicroscopy, 2007, 108, 58-67.	1.9	14
87	Theory of dynamical scattering in near-edge electron energy loss spectroscopy. Physical Review B, 2009, 80, .	3.2	14
88	Energy-filtered transmission electron microscopy based on inner-shell ionization. Ultramicroscopy, 2010, 110, 981-990.	1.9	14
89	HAADF-STEM observations of a $\Sigma$ 13 grain boundary in $\text{Al}_2\text{O}_3$ from two orthogonal directions. Philosophical Magazine Letters, 2010, 90, 539-546.	1.2	13
90	Large angle illumination enabling accurate structure reconstruction from thick samples in scanning transmission electron microscopy. Ultramicroscopy, 2019, 197, 112-121.	1.9	12

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91	Quantitative structure retrieval using scanning transmission electron microscopy. Acta Crystallographica Section A: Foundations and Advances, 2005, 61, 397-404.	0.3	11
92	Image Contrast in Aberration-Corrected Scanning Confocal Electron Microscopy. Advances in Imaging and Electron Physics, 2010, 162, 45-76.	0.2	11
93	Elemental mapping in scanning transmission electron microscopy. Journal of Physics: Conference Series, 2010, 241, 012061.	0.4	11
94	Interface location by depth sectioning using a low-angle annular dark field detector. Ultramicroscopy, 2012, 113, 131-138.	1.9	11
95	A quantum mechanical exploration of phonon energy-loss spectroscopy using electrons in the aloof beam geometry. Microscopy (Oxford, England), 2018, 67, i24-i29.	1.5	11
96	Phase-contrast imaging of multiply-scattering extended objects at atomic resolution by reconstruction of the scattering matrix. Physical Review Research, 2021, 3, .	3.6	11
97	Atomic structure, energetics, and chemical bonding of Y doped $\text{La}_{1-x}\text{Al}_x\text{O}_3$ grain boundaries in $\text{LaAlO}_3$ . Philosophical Magazine, 2013, 93, 1158-1171.	1.6	10
98	Practical Aspects of Removing the Effects of Elastic and Thermal Diffuse Scattering from Spectroscopic Data for Single Crystals. Microscopy and Microanalysis, 2014, 20, 1078-1089.	0.4	10
99	Influence of experimental conditions on atom column visibility in energy dispersive X-ray spectroscopy. Ultramicroscopy, 2016, 171, 1-7.	1.9	10
100	A menu of electron probes for optimising information from scanning transmission electron microscopy. Ultramicroscopy, 2018, 184, 143-155.	1.9	10
101	The effect of vacancies on the annular dark field image contrast of grain boundaries: A SrTiO <sub>3</sub> case study. Ultramicroscopy, 2011, 111, 1531-1539.	1.9	9
102	Stabilisation of Fe <sub>2</sub> O <sub>3</sub> -rich Perovskite Nanophase in Epitaxial Rare-earth Doped BiFeO <sub>3</sub> Films. Scientific Reports, 2015, 5, 13066.	3.3	9
103	Low magnification differential phase contrast imaging of electric fields in crystals with fine electron probes. Ultramicroscopy, 2016, 169, 69-79.	1.9	9
104	What atomic resolution annular dark field imaging can tell us about gold nanoparticles on $\text{TiO}_2(110)$ . Ultramicroscopy, 2009, 109, 1435-1446.	1.9	8
105	Simulation and Interpretation of Images. , 2011, , 247-289.		8
106	Accuracy and precision of thickness determination from position-averaged convergent beam electron diffraction patterns using a single-parameter metric. Ultramicroscopy, 2017, 181, 86-96.	1.9	8
107	Atomic number contrast in high angle annular dark field imaging of crystals. Materials Science and Technology, 2008, 24, 660-666.	1.6	7
108	Annular Bright-Field Scanning Transmission Electron Microscopy: Direct and Robust Atomic-Resolution Imaging of Light Elements in Crystalline Materials. Microscopy Today, 2017, 25, 36-41.	0.3	7

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109	Scanning transmission electron microscopy imaging dynamics at low accelerating voltages. <i>Ultramicroscopy</i> , 2011, 111, 999-1013.	1.9	6
110	High contrast at low dose using a single, defocussed transmission electron micrograph. <i>Micron</i> , 2019, 124, 102701.	2.2	6
111	Optimizing Experimental Conditions for Accurate Quantitative Energy-Dispersive X-ray Analysis of Interfaces at the Atomic Scale. <i>Microscopy and Microanalysis</i> , 2021, 27, 528-542.	0.4	6
112	A Three-Dimensional Reconstruction Algorithm for Scanning Transmission Electron Microscopy Data from a Single Sample Orientation. <i>Microscopy and Microanalysis</i> , 2022, 28, 1632-1640.	0.4	6
113	Scattering Matrix Determination in Crystalline Materials from 4D Scanning Transmission Electron Microscopy at a Single Defocus Value. <i>Microscopy and Microanalysis</i> , 2021, 27, 744-757.	0.4	5
114	Factors limiting quantitative phase retrieval in atomic-resolution differential phase contrast scanning transmission electron microscopy using a segmented detector. <i>Ultramicroscopy</i> , 2022, 233, 113457.	1.9	5
115	Prospects for 3D imaging of dopant atoms in ceramic interfaces. <i>Journal of Electron Microscopy</i> , 2010, 59, S29-S38.	0.9	4
116	Quantitative STEM: Experimental Methods and Applications. <i>Journal of Physics: Conference Series</i> , 2012, 371, 012053.	0.4	4
117	Atomic structure characterization of stacking faults on the {111} plane in $\alpha$ -alumina by scanning transmission electron microscopy. <i>AIP Conference Proceedings</i> , 2016, , .	0.4	4
118	Letter to the Editor: Limitations to the Measurement of Oxygen Concentrations by HRTEM Imposed by Surface Roughness. <i>Microscopy and Microanalysis</i> , 2005, 11, 111-113.	0.4	3
119	Theoretical interpretation of electron energy-loss spectroscopic images. <i>AIP Conference Proceedings</i> , 2008, , .	0.4	3
120	Absolute-Scale Quantitative Energy Dispersive X-ray Analysis in Aberration-Corrected Scanning Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2015, 21, 1079-1080.	0.4	3
121	Understanding electron magnetic circular dichroism in a transition potential approach. <i>Physical Review B</i> , 2018, 97, .	3.2	3
122	Inelastic Scattering in Electron Backscatter Diffraction and Electron Channeling Contrast Imaging. <i>Microscopy and Microanalysis</i> , 2020, 26, 1147-1157.	0.4	3
123	Linear imaging theory for differential phase contrast and other phase imaging modes in scanning transmission electron microscopy. <i>Ultramicroscopy</i> , 2022, , 113580.	1.9	3
124	Three-dimensional imaging using aberration-corrected scanning transmission and confocal electron microscopy. <i>Journal of Physics: Conference Series</i> , 2008, 126, 012036.	0.4	2
125	Atomic-Resolution Scanning Transmission Electron Microscopy with Segmented Annular All Field Detector. <i>Microscopy and Microanalysis</i> , 2014, 20, 64-65.	0.4	2
126	Imaging Low Z Materials in Crystalline Environments Via Scanning Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2019, 25, 1732-1733.	0.4	2



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127	Atomic-Resolution EELS in Aberration-Corrected STEM. <i>Microscopy and Microanalysis</i> , 2003, 9, 852-853.	0.4	1
128	Depth sectioning using electron energy loss spectroscopy. <i>Journal of Physics: Conference Series</i> , 2008, 126, 012037.	0.4	1
129	Quantitative transmission electron microscopy at atomic resolution. <i>Journal of Physics: Conference Series</i> , 2012, 371, 012009.	0.4	1
130	Quantitative EDX and EELS Elemental Mapping at Atomic Resolution. <i>Microscopy and Microanalysis</i> , 2014, 20, 570-571.	0.4	1
131	Direct Electromagnetic Structure Observation by Aberration-corrected Differential Phase Contrast Scanning Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2016, 22, 906-907.	0.4	1
132	Quantitative Atomic Resolution Differential Phase Contrast Imaging Using a Segmented Area All Field Detector. <i>Microscopy and Microanalysis</i> , 2016, 22, 504-505.	0.4	1
133	Facilitating Quantitative Analysis of Atomic Scale 4D STEM Datasets. <i>Microscopy and Microanalysis</i> , 2016, 22, 474-475.	0.4	1
134	Absolute-Scale Comparison with Simulation for Quantitative Energy-Dispersive X-Ray Spectroscopy in Atomic-Resolution Scanning Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2017, 23, 388-389.	0.4	1
135	Three-Dimensional Point Defect Imaging by Large-angle Illumination STEM. <i>Microscopy and Microanalysis</i> , 2017, 23, 424-425.	0.4	1
136	Quantitative Specimen Electric Potential Maps Using Segmented and Pixel Detectors in Scanning Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2017, 23, 442-443.	0.4	1
137	Rapid Simulation of Elemental Maps in Core-Loss Electron Energy Loss Spectroscopy. <i>Microscopy and Microanalysis</i> , 2019, 25, 574-575.	0.4	1
138	Direct Imaging of Dopant Segregation in a Ceramic Grain Boundary. <i>Materia Japan</i> , 2009, 48, 639-639.	0.1	0
139	Prospects for 3D Imaging of Dopant Atoms in Ceramic Materials. <i>Microscopy and Microanalysis</i> , 2009, 15, 44-45.	0.4	0
140	Atomic Structures and Properties of Ceramic Interfaces – Combination of Cs-Corrected STEM and First Principles Calculations. <i>Microscopy and Microanalysis</i> , 2010, 16, 1466-1467.	0.4	0
141	Counting atoms with quantitative scanning transmission electron microscopy. <i>Acta Crystallographica Section A: Foundations and Advances</i> , 2011, 67, C105-C105.	0.3	0
142	Addressing Detector Non-Uniformity in Scanning Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2013, 19, 600-601.	0.4	0
143	Tracking Dopant Diffusion Pathways inside Bulk Materials. <i>Microscopy and Microanalysis</i> , 2014, 20, 50-51.	0.4	0
144	Polar Oxide Interface Characterization by Differential Phase Contrast STEM. <i>Microscopy and Microanalysis</i> , 2014, 20, 1034-1035.	0.4	0

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145	Highly Accurate Real Space Nanometrology Using Revolving Scanning Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2015, 21, 2245-2246.	0.4	0
146	Annular Bright Field Scanning Transmission Electron Microscopy - Direct and Robust Atomic-Resolution Imaging of Light Elements in Crystalline Materials. <i>Microscopy and Microanalysis</i> , 2015, 21, 1939-1940.	0.4	0
147	Influence of Convergence Angle and Finite Effective Source Size for Quantitative Atomic Resolution EDXS. <i>Microscopy and Microanalysis</i> , 2015, 21, 1093-1094.	0.4	0
148	Quantitative Electron Microscopy and the Application by Single Electron Signals. <i>Microscopy and Microanalysis</i> , 2015, 21, 1449-1450.	0.4	0
149	Dopant Quantification by Atomic-scale Energy Dispersive X-ray Analysis. <i>Microscopy and Microanalysis</i> , 2015, 21, 819-820.	0.4	0
150	Simulating Inelastic Scattering in Scanning Transmission Electron Microscopy using $\hat{1}/4$ STEM. <i>Microscopy and Microanalysis</i> , 2015, 21, 1885-1886.	0.4	0
151	ABF-STEM Characterization of the <u>1</u> Stacking Fault in Alumina. <i>Materia Japan</i> , 2016, 55, 610-610.	0.1	0
152	Making every electron count: materials characterization by quantitative analytical scanning transmission electron microscopy. <i>Microscopy and Microanalysis</i> , 2016, 22, 1430-1431.	0.4	0
153	Probing the Effects of Electron Channelling on EDX Quantification. <i>Microscopy and Microanalysis</i> , 2017, 23, 392-393.	0.4	0
154	Understanding Imaging and Energy-loss Spectra Due to Phonon Excitation. <i>Microscopy and Microanalysis</i> , 2017, 23, 1536-1537.	0.4	0
155	Probe Shaping for Quantitative DPC-STEM Using Segmented Detectors. <i>Microscopy and Microanalysis</i> , 2018, 24, 916-917.	0.4	0
156	Pushing the Limits of Absolute Scale Energy Dispersive X-ray Quantification. <i>Microscopy and Microanalysis</i> , 2019, 25, 968-969.	0.4	0
157	Structure Retrieval of Strongly Scattering Materials in the Transmission Electron Microscope. <i>Microscopy and Microanalysis</i> , 2019, 25, 76-77.	0.4	0
158	Image contrast in atomic resolution high-angle annular dark-field images. <i>Acta Crystallographica Section A: Foundations and Advances</i> , 2008, 64, C65-C65.	0.3	0
159	Direct Imaging of Single Dopant Atoms in a Buried Crystalline Interface by Scanning Transmission Electron Microscopy. <i>Journal of the Vacuum Society of Japan</i> , 2011, 54, 270-274.	0.3	0
160	Modelling thermal scattering and solving structures using Z-contrast imaging. <i>Acta Crystallographica Section A: Foundations and Advances</i> , 2011, 67, C155-C156.	0.3	0
161	Real-Space Imaging of Light Elements by Annular Bright-Field Scanning Transmission Electron Microscopy. <i>Nihon Kessho Gakkaishi</i> , 2013, 55, 362-368.	0.0	0
162	Complex Point Defect Structure in Cubic Boron Nitride. <i>Materia Japan</i> , 2016, 55, 609-609.	0.1	0

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163	Electric Field Imaging at Atomic Resolution by DPC STEM. <i>Materia Japan</i> , 2019, 58, 104-104.	0.1	0
164	New Approach to Quantitative ADF STEM. , 2008, , 129-130.		0